

Docket No. 12054-0018



IFW  
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Murakami et al.

Serial No.: 10/601,576

Examiner: Speer, Timothy M.

Filing Date: June 24, 2003

Art Unit: 1775

For: Silicon Single Crystal Wafer for Particle Monitor

**AMENDMENT**

Commissioner of Patents  
PO Box 1450  
Alexandria, VA 22303

Sir:

This Amendment is being filed responsive to the Office Action dated November 25, 2005. Please amend the application as follows:

05/22/2006 MBEYENE1 00000029 10601576

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